

SN54ALS804A, SN54AS804B, SN74ALS804A, SN74AS804B HEX 2-INPUT NAND DRIVERS

SDAS022C – DECEMBER 1982 – REVISED JANUARY 1995

- High Capacitive-Drive Capability
- 'ALS804A Has Typical Delay Time of 4 ns ($C_L = 50$ pF) and Typical Power Dissipation of 3.4 mW Per Gate
- 'AS804B Has Typical Delay Time of 2.6 ns ($C_L = 50$ pF) and Typical Power Dissipation of Less Than 9 mW Per Gate
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

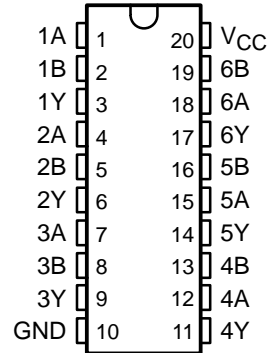
These devices contain six independent 2-input NAND drivers. They perform the Boolean functions $Y = \overline{A \cdot B}$ or $Y = \overline{A} + \overline{B}$ in positive logic.

The SN54ALS804A and SN54AS804B are characterized for operation over the full military temperature range of -55°C to 125°C . The SN74ALS804A and SN74AS804B are characterized for operation from 0°C to 70°C .

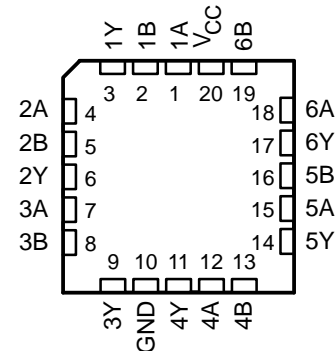
FUNCTION TABLE
(each driver)

INPUTS		OUTPUT Y
A	B	
H	H	L
L	X	H
X	L	H

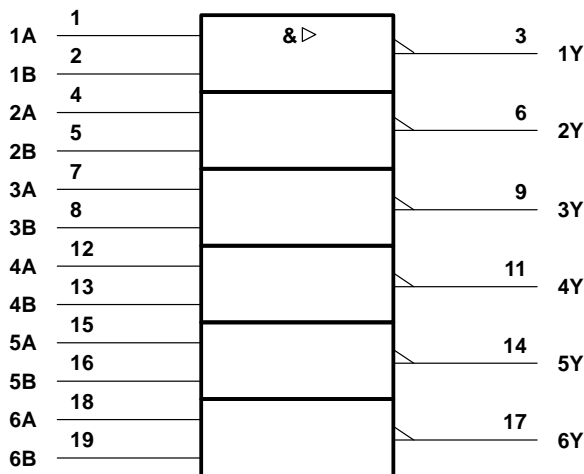
SN54ALS804A, SN54AS804B ... J PACKAGE
SN74ALS804A, SN74AS804B ... DW OR N PACKAGE
(TOP VIEW)



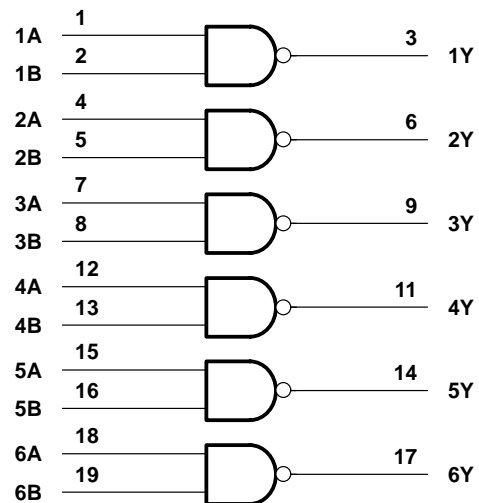
SN54ALS804A, SN54AS804B ... FK PACKAGE
(TOP VIEW)



logic symbol†



logic diagram (positive logic)



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN54ALS804A, SN54AS804B, SN74ALS804A, SN74AS804B HEX 2-INPUT NAND DRIVERS

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V_{CC}	7 V
Input voltage, V_I	7 V
Operating free-air temperature range, T_A : SN54ALS804A	–55°C to 125°C
SN74ALS804A	0°C to 70°C
Storage temperature range	–65°C to 150°C

[†] Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS804A			SN74ALS804A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
I_{OH}	High-level output current			–12			–15	mA
I_{OL}	Low-level output current			12			24	mA
T_A	Operating free-air temperature	–55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54ALS804A			SN74ALS804A			UNIT
			MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	
V_{IK}	$V_{CC} = 4.5$ V,	$I_I = -18$ mA			–1.2			–1.2	V
V_{OH}	$V_{CC} = 4.5$ V to 5.5 V,	$I_{OH} = -0.4$ mA	$V_{CC} - 2$			$V_{CC} - 2$			V
	$V_{CC} = 4.5$ V	$I_{OH} = -3$ mA	2.4	3.2		2.4	3.2		
		$I_{OH} = -12$ mA	2						
		$I_{OH} = -15$ mA				2			
V_{OL}	$V_{CC} = 4.5$ V	$I_{OL} = 12$ mA		0.25	0.4		0.25	0.4	V
		$I_{OL} = 24$ mA					0.35	0.5	
I_I	$V_{CC} = 5.5$ V,	$V_I = 7$ V			0.1			0.1	mA
I_{IH}	$V_{CC} = 5.5$ V,	$V_I = 2.7$ V			20			20	μA
I_{IL}	$V_{CC} = 5.5$ V,	$V_I = 0.4$ V			–0.1			–0.1	mA
I_{O}^{\S}	$V_{CC} = 5.5$ V,	$V_O = 2.25$ V	–20		–112	–30		–112	mA
I_{CCH}	$V_{CC} = 5.5$ V,	$V_I = 0$		0.9	2.5		0.9	2.5	mA
I_{CCL}	$V_{CC} = 5.5$ V,	$V_I = 4.5$ V		7	12		7	12	mA

[‡] All typical values are at $V_{CC} = 5$ V, $T_A = 25^\circ\text{C}$.

^{\S} The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS} .



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switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500 Ω, T _A = MIN to MAX†				UNIT
			SN54ALS804A		SN74ALS804A		
			MIN	MAX	MIN	MAX	
t _{PLH}	A or B	Y	2	9	2	7	ns
t _{PHL}			2	9	2	8	

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Operating free-air temperature range, T _A : SN54AS804B	–55°C to 125°C
SN74AS804B	0°C to 70°C
Storage temperature range	–65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions§

		SN54AS804B			SN74AS804B			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V _{IH}	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.8			0.8	V
I _{OH}	High-level output current			–40			–48	mA
I _{OL}	Low-level output current			40			48	mA
T _A	Operating free-air temperature	–55		125	0		70	°C

§ These high sink- or source-current devices are not recommended for use above 40 MHz.

SN54ALS804A, SN54AS804B, SN74ALS804A, SN74AS804B

HEX 2-INPUT NAND DRIVERS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		SN54AS804B		SN74AS804B		UNIT
			MIN	TYP†	MAX	MIN	
V _{IK}	V _{CC} = 4.5 V, I _I = −18 mA		−1.2		−1.2		V
V _{OH}	V _{CC} = 4.5 V to 5.5 V, I _{OH} = −2 mA		V _{CC} − 2		V _{CC} − 2		V
	V _{CC} = 4.5 V	I _{OH} = −3 mA	2.4	3.2	2.4	3.2	
		I _{OH} = −40 mA	2				
		I _{OH} = −48 mA			2		
V _{OL}	V _{CC} = 4.5 V	I _{OL} = 40 mA	0.25	0.5			V
		I _{OL} = 48 mA			0.35	0.5	
I _I	V _{CC} = 5.5 V, V _I = 7 V	0.1		0.1		mA	
I _{IH}	V _{CC} = 5.5 V, V _I = 2.7 V	20		20		μA	
I _{IL}	V _{CC} = 5.5 V, V _I = 0.4 V	−0.5		−0.5		mA	
I _O ‡	V _{CC} = 5.5 V, V _O = 2.25 V	−50	−200	−50	−200	mA	
I _{CC} H	V _{CC} = 5.5 V, V _I = 0	3.5	5	3.5	5	mA	
I _{CC} L	V _{CC} = 5.5 V, V _I = 4.5 V	16	27	16	27	mA	

† All typical values are at $V_{CC} = 5\text{ V}$, $T_A = 25^\circ\text{C}$.

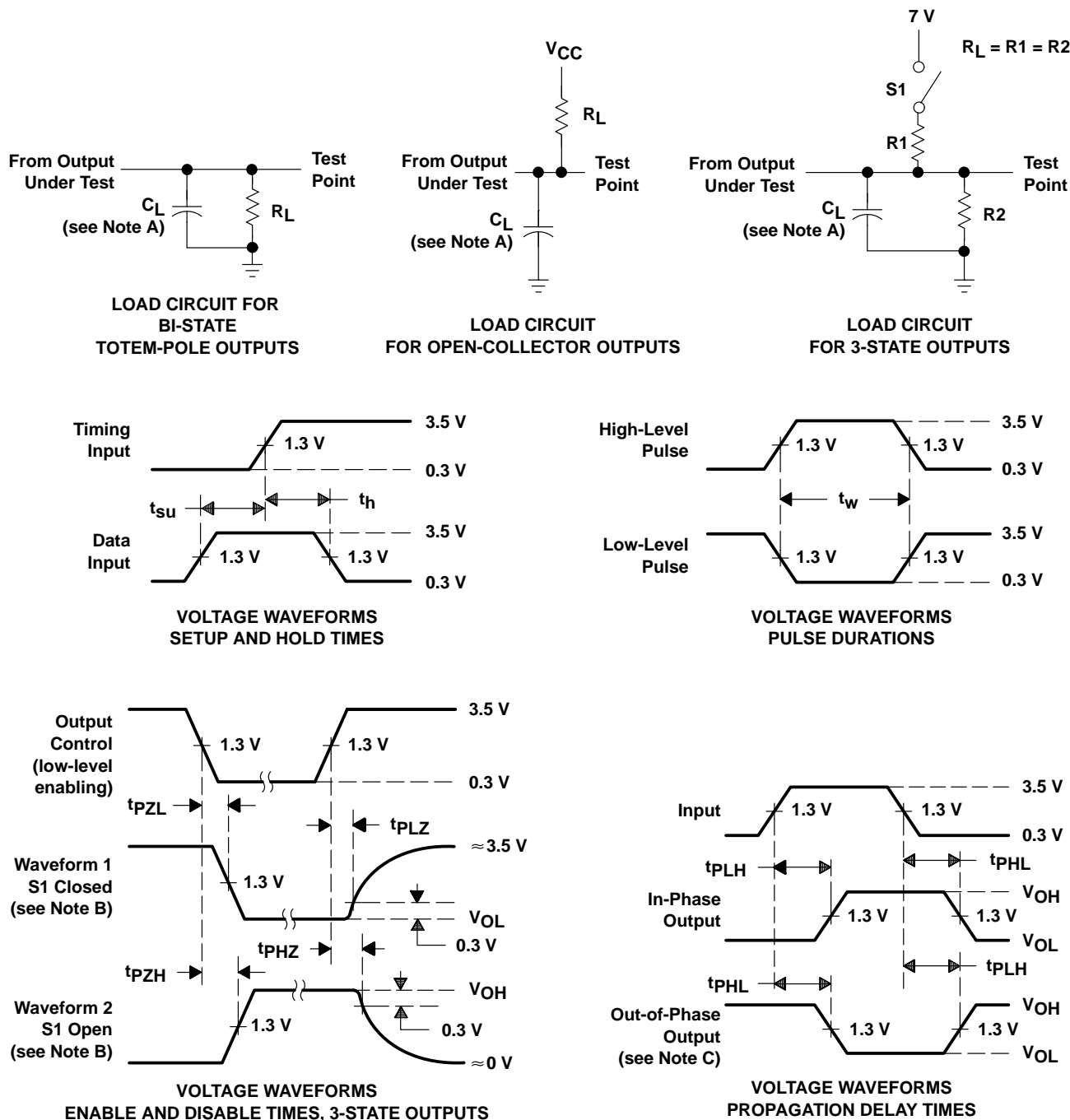
‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I_{OS} .

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 4.5 V to 5.5 V, C _L = 50 pF, R _L = 500 Ω, T _A = MIN to MAX§				UNIT
			SN54AS804B		SN74AS804B		
			MIN	MAX	MIN	MAX	
t _{PLH}	A or B	Y	1	5	1	4	ns
t _{PHL}			1	5	1	4	

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

PARAMETER MEASUREMENT INFORMATION
SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



- NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
D. All input pulses have the following characteristics: $PRR \leq 1$ MHz, $t_r = t_f = 2$ ns, duty cycle = 50%.
E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms

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